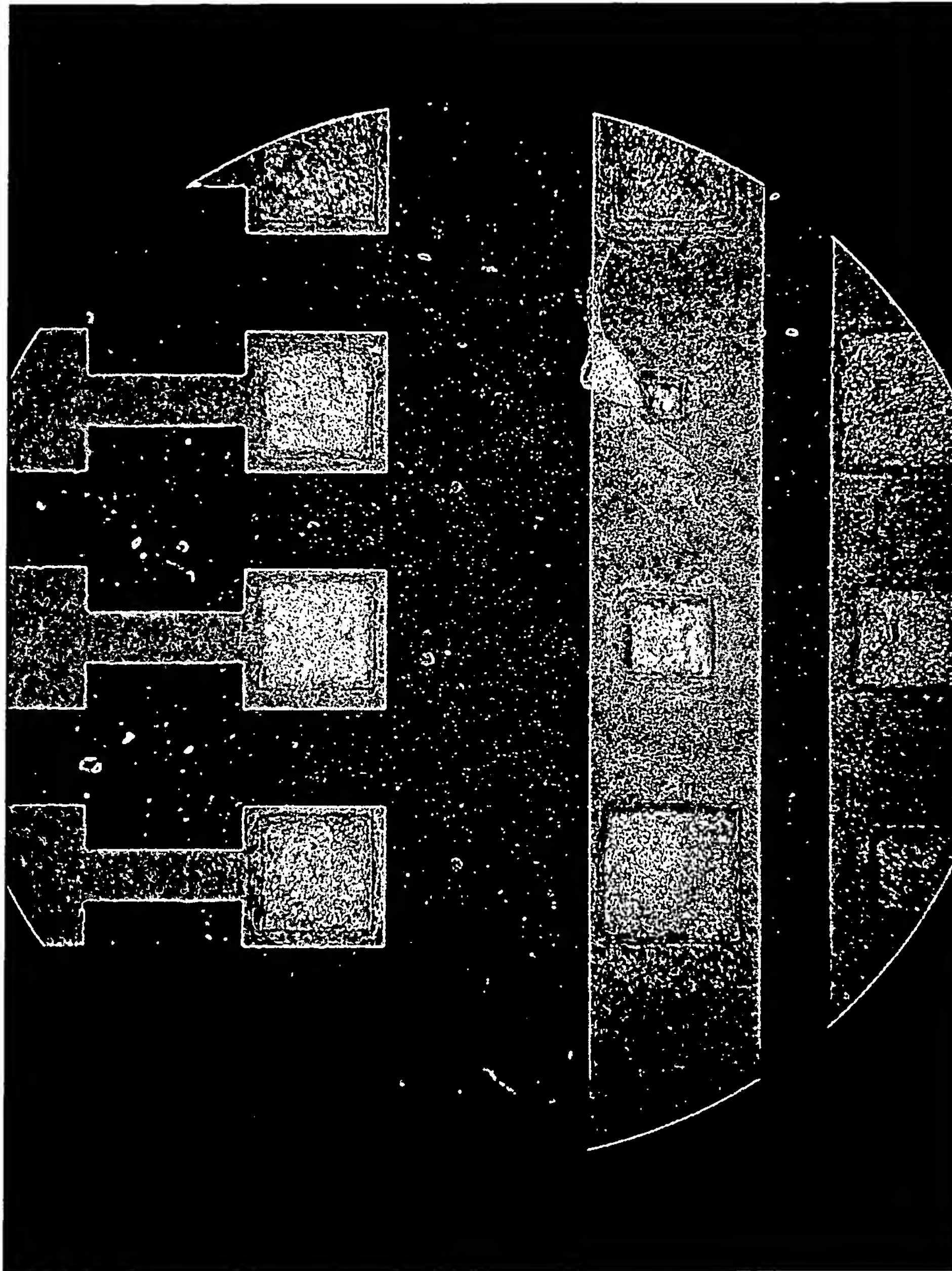


Fig.1 – Fabrication Steps



**Fig. 2 – Polymer Bumps Under Optical Microscope**

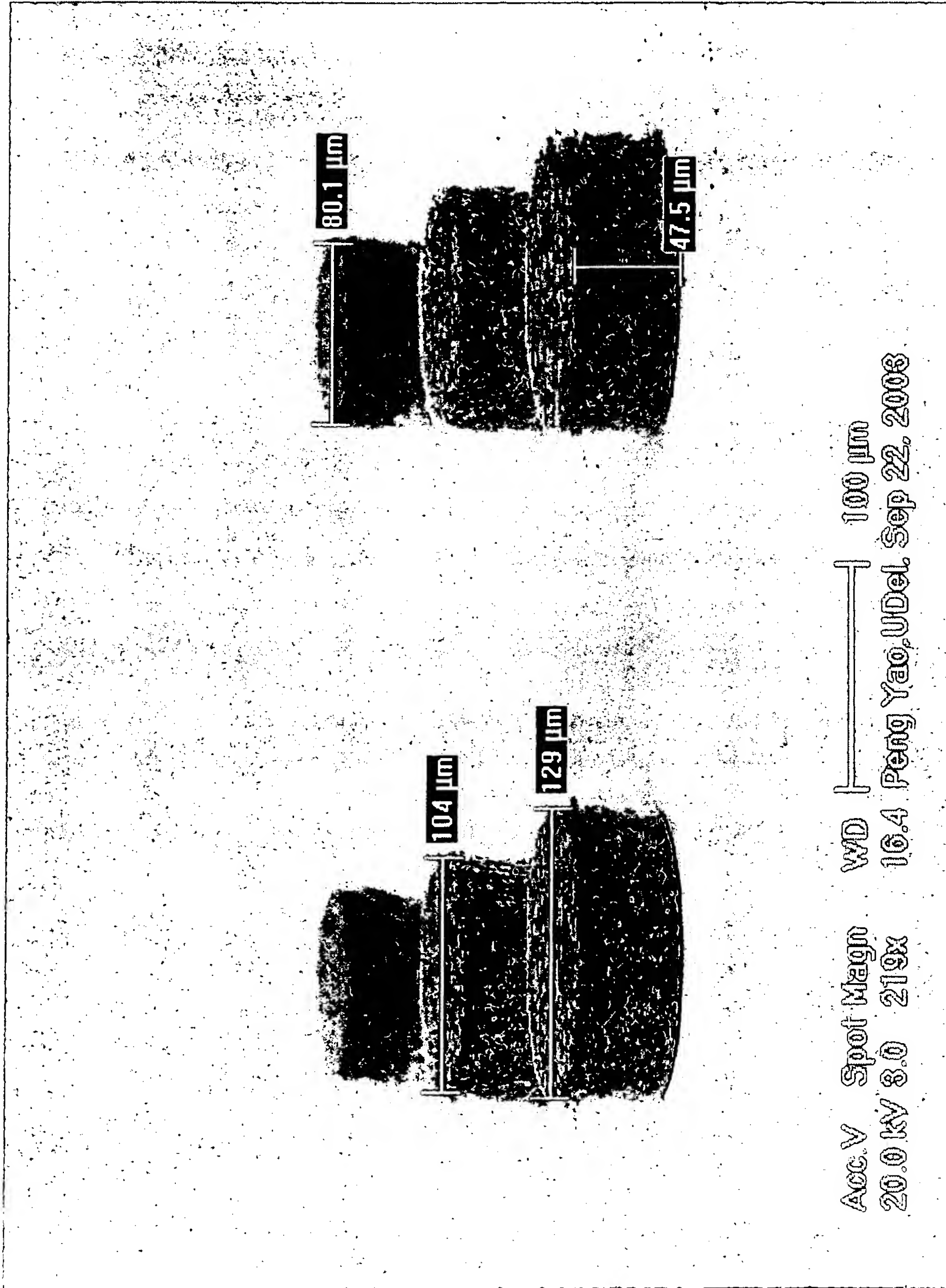
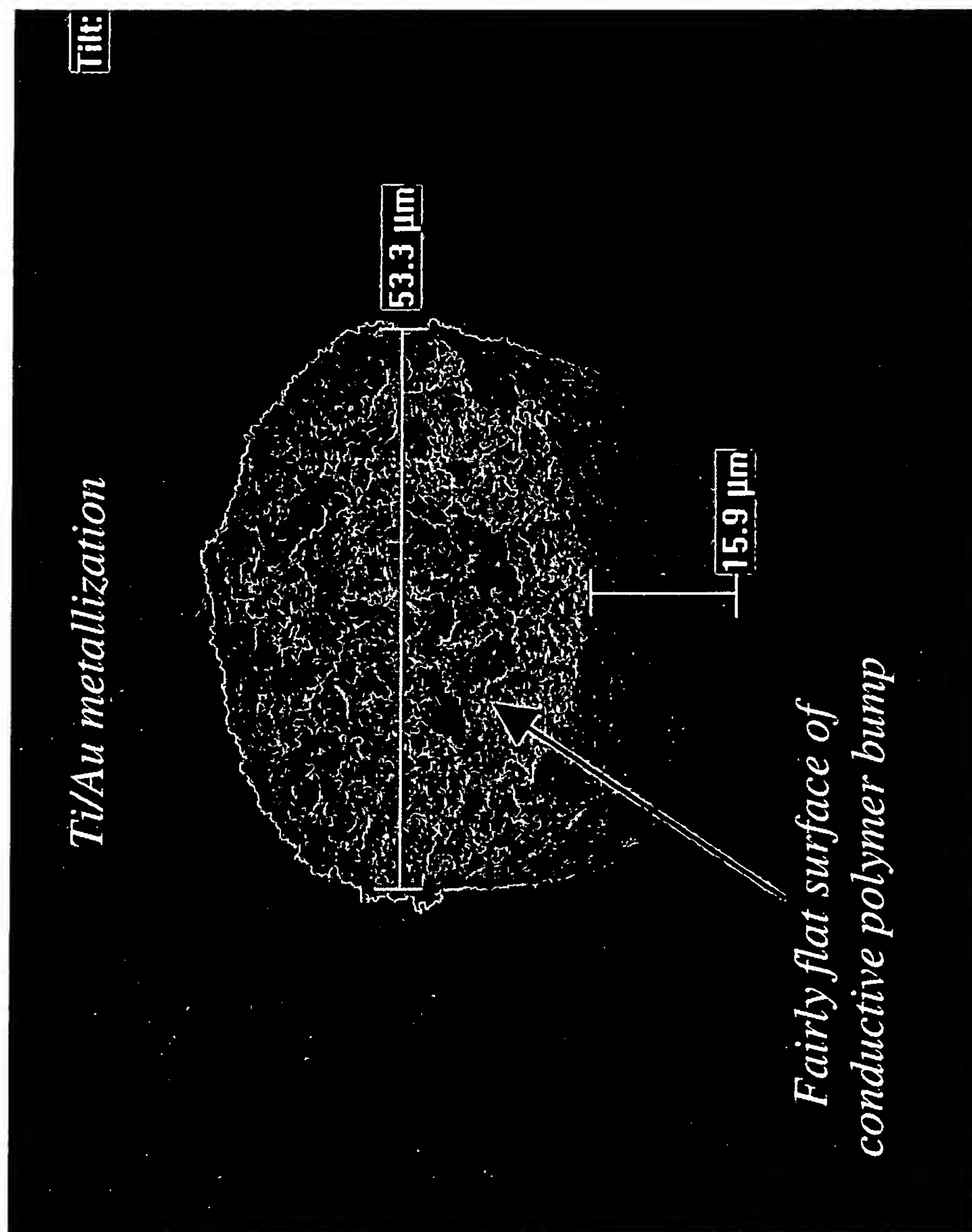
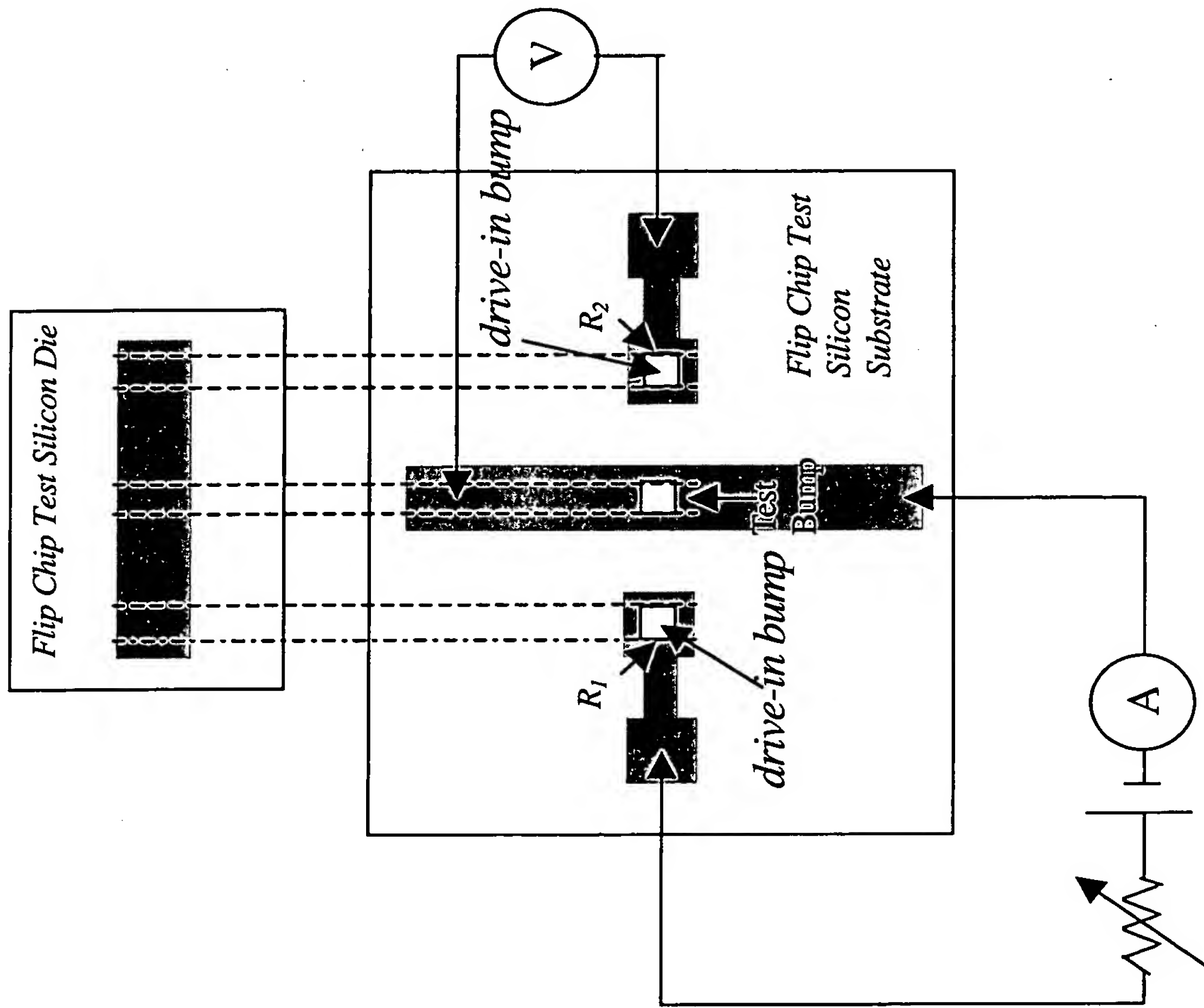


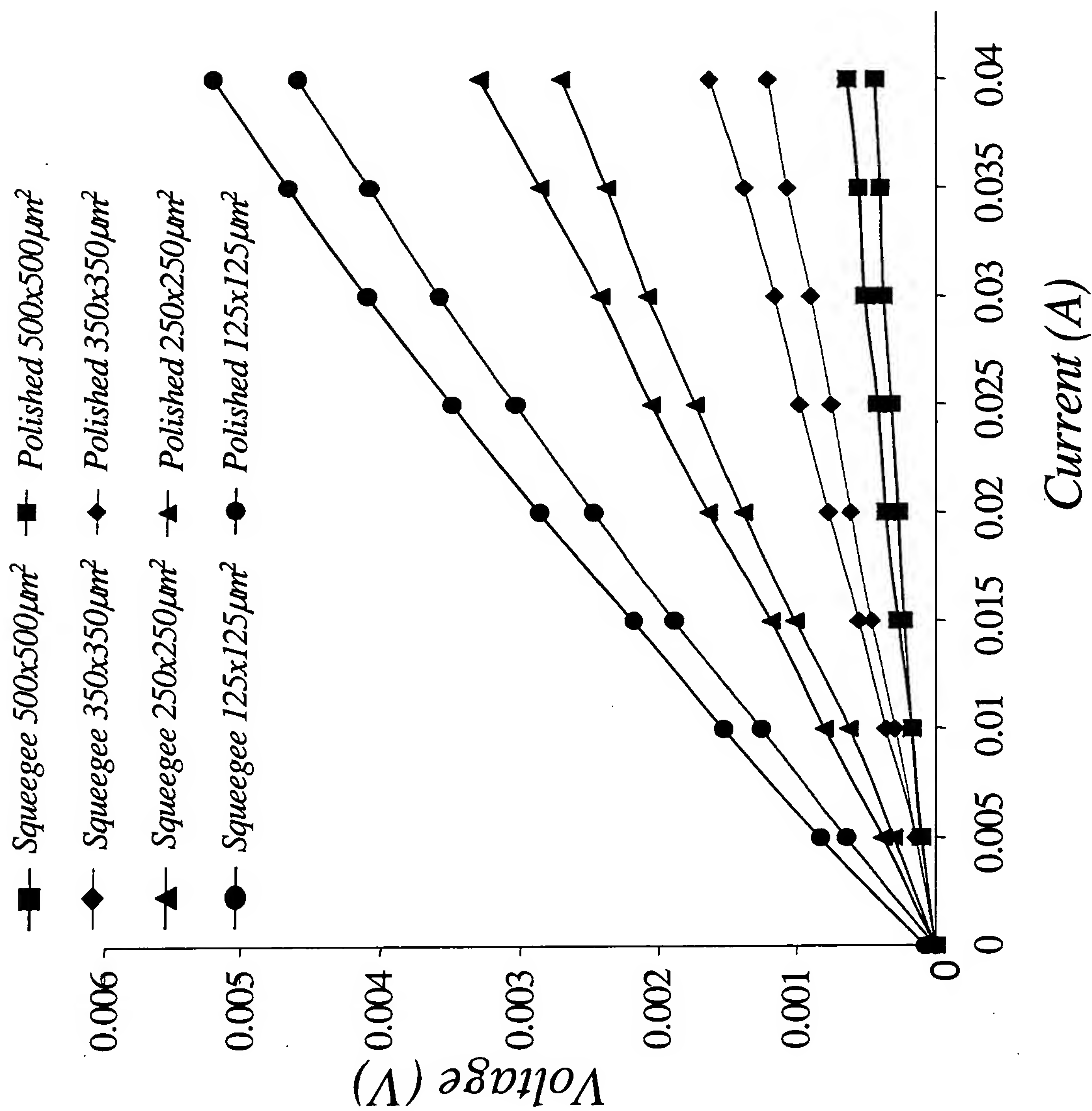
Fig. 3 - SEM View of Surface of Polished Polymer Bumps



**Fig. 4 - SEM View of Surface of Polished Conductive Polymer Bumps**

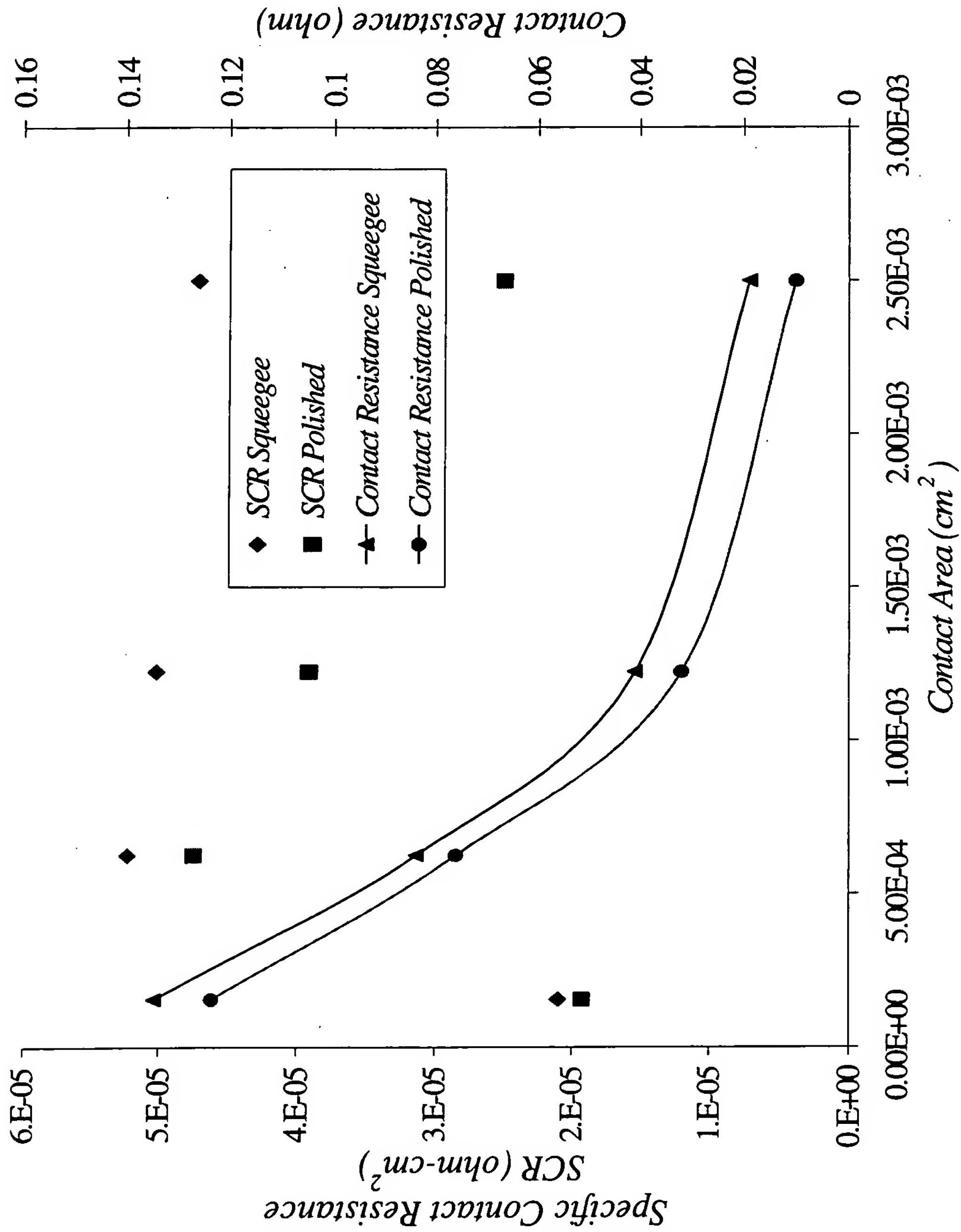


**Fig. 5 - Contact Resistance Test Setup**



**Fig. 6 - Contact Resistance Comparison**





**Fig. 7 - Contact Resistance and Specific Contact Resistance**

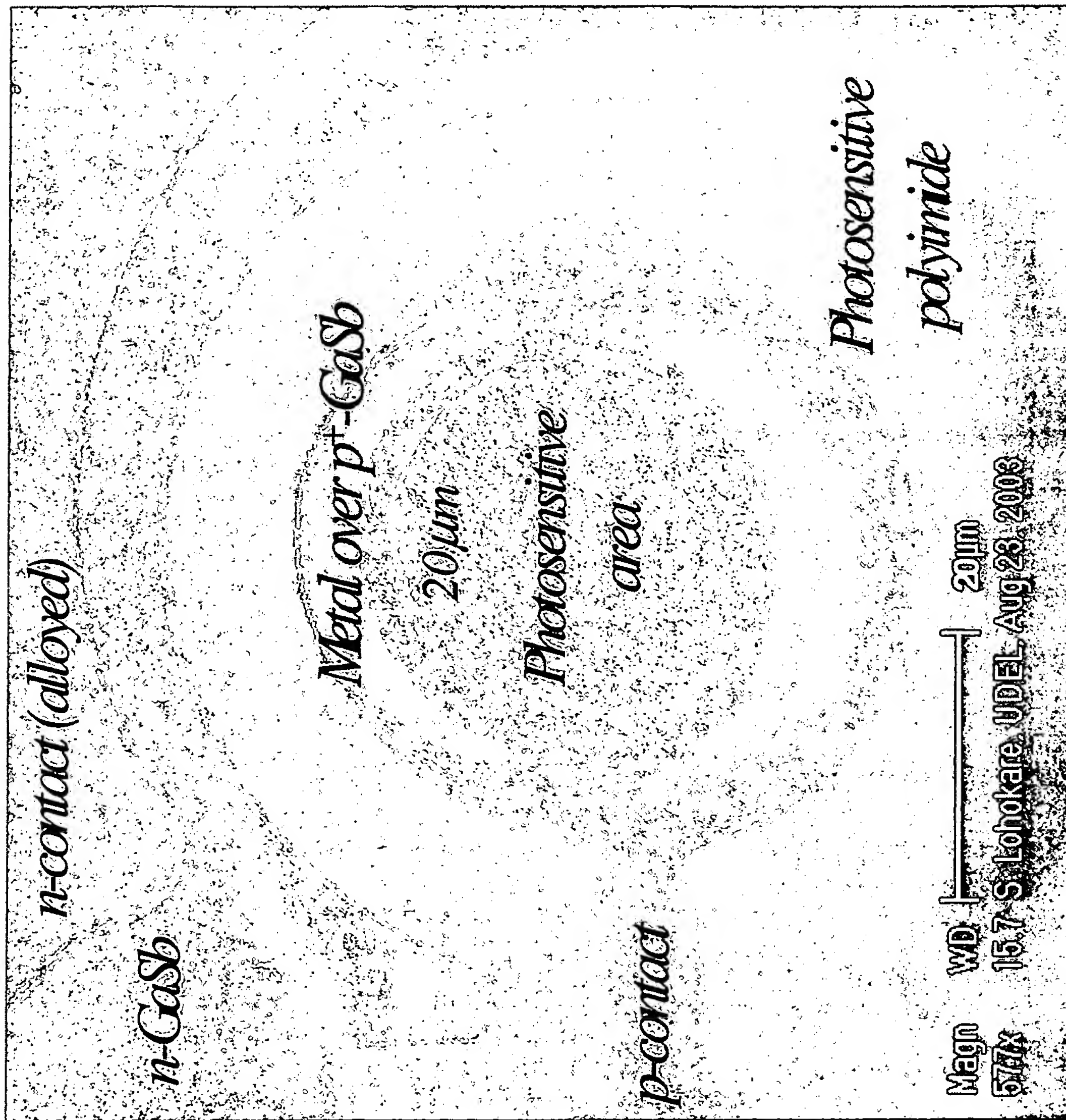


Fig. 8 – SEM View of AlGaAsSb/AlGaSb p-i-n Photodetector



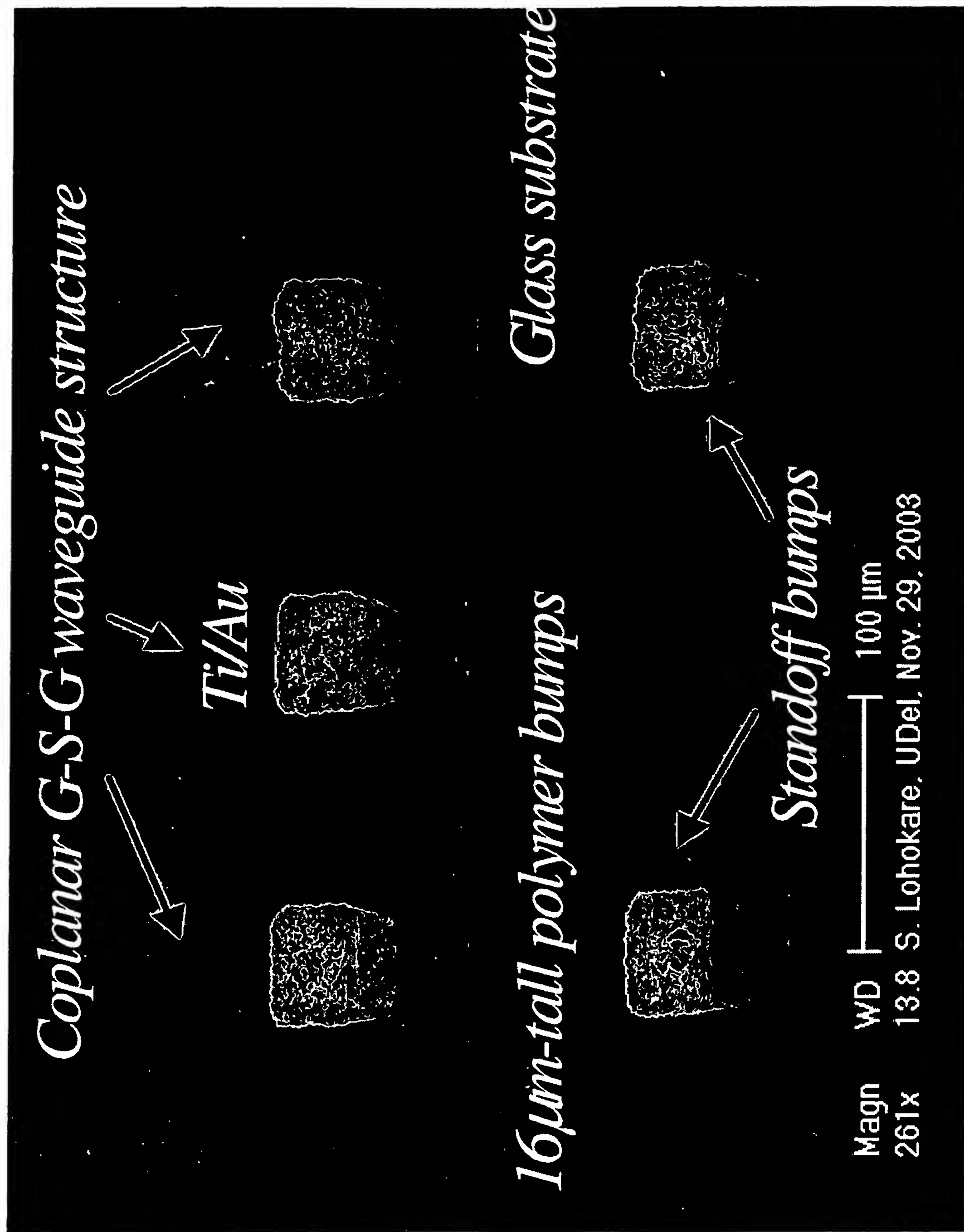
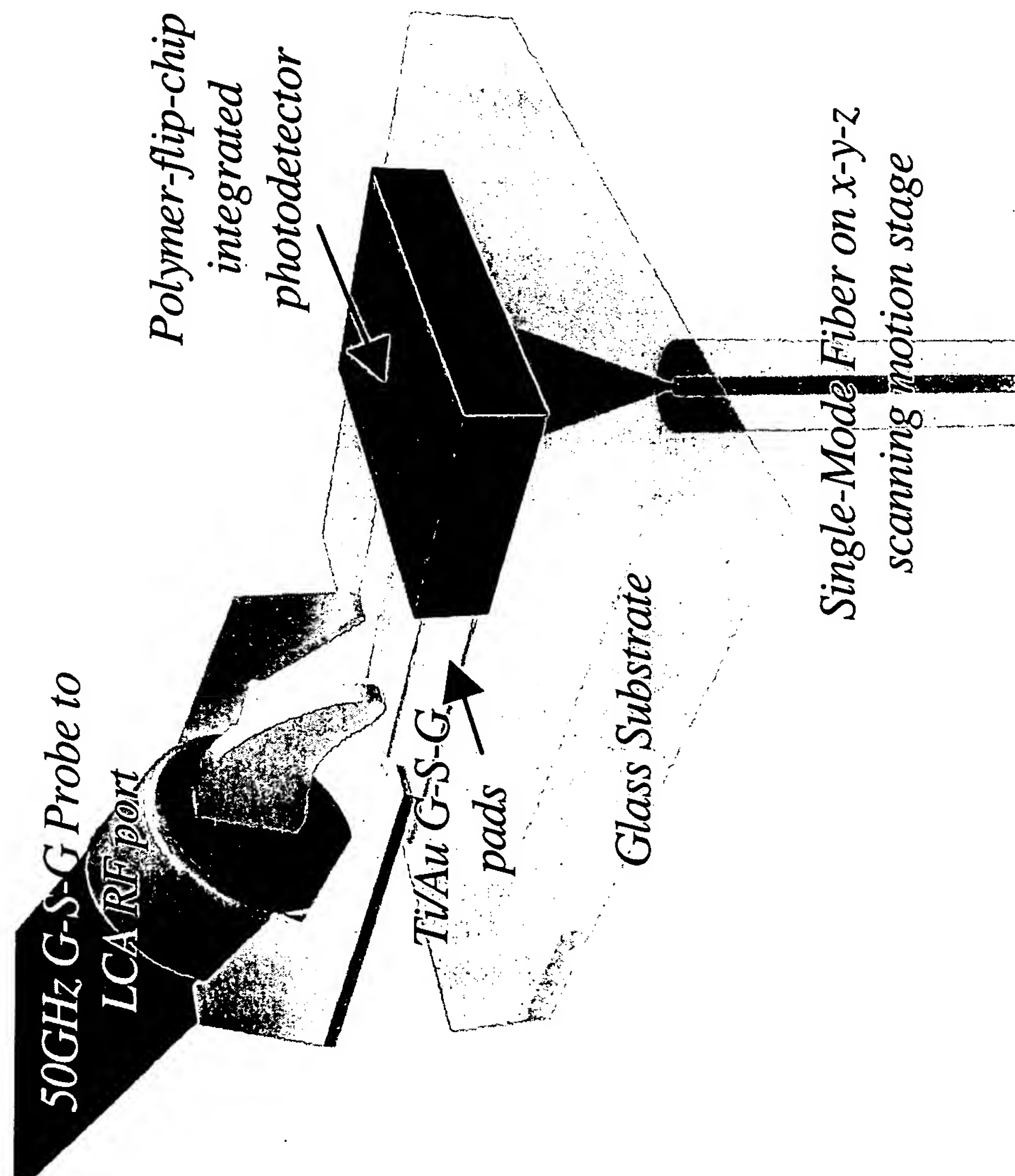
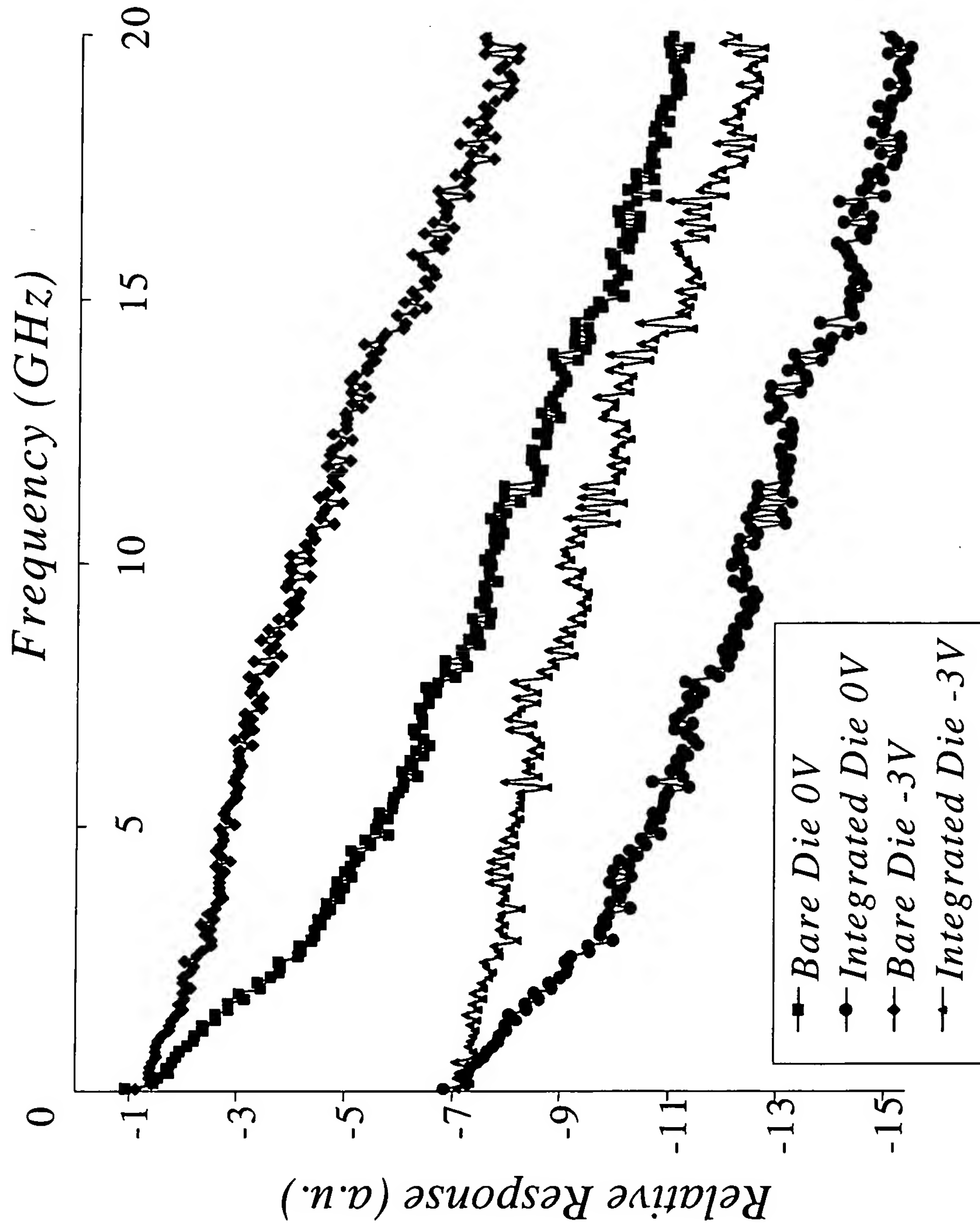


Fig. 9 – SEM View of Conductive Adhesive Bumps on Coplanar Waveguide



**Fig. 10 – Schematic of Test Setup for PFC Integrated p-i-n Detector**



**Fig. 11 – Normalized BW Response for Bare-Die and PFC Integrated *p-i-n* Detector**

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